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Nanosurf LensAFM Webinar:

Advancements in Instrumentation for Surface Inspection and Defect Analysis

Webinar Date: 09 May 2012
11:00AM EDT, 8:00AM PDT, 17:00 CEST

Speaker: Dr. David Faddis, Ph.D.
Director of Technology and Applications, Nanosurf Inc.



The Nanosurf LensAFM is an atomic force microscope (AFM) that may be used in conjunction with almost any upright optical microscope or optical profilometer. The combined LensAFM/optical platform provides a complementary imaging system that greatly extends the resolution and measuring capabilities of these individual instruments.

This webinar will highlight:

- Ease of adaptation with multiple optical platforms
- Synergy and convenience of combining optical and 3D topographical information in the same place
- Examples of industrial applications that have benefited from the combined platform

Applications:

- Roughness Measurements, Defect Analysis, Edge Radius, Step Heights
- Material Properties: Hardness, wear analysis, Conductance/Resistance, Magnetism

Who Should Attend:

- Quality Assurance Professionals, Engineers, and Management
- Those interested in non-destructive testing
- Research and Development Teams
- Academic Staff/Students

Register Free at <https://www4.gotomeeting.com/register/223072431>

Please retain the following password: Nsf*123. It will be required to join the webinar.

We hope you will be able to join us on May 9th!